

SEMiX[®] 3p

Trench IGBT Modules

SEMiX223GB12M7p

Features*

- Homogeneous Si
- Trench = Trenchgate technology
 V_{CE(sat)} with positive temperature
- coefficient
- High overload capability
- Low loss high density IGBTs
- Press-fit pins as auxiliary contacts
- UL recognized, file no. E63532

Typical Applications

- AC inverter drives
- UPS
- Renewable energy systems

Remarks

- Product reliability results are valid for $T_j=150^{\circ}C$ (recommended $T_{j,op}=-40...+150^{\circ}C$)
- V_{isol} between temperature sensor and power section is only 2500V
- For storage and case temperature with TIM see document "TP(*) SEMiX 3p"



| Absolute | Maximum Ratin | gs | | |
|---------------------|---|-------------------------|---------|------|
| Symbol | Conditions | | Values | Unit |
| IGBT | | | | |
| V _{CES} | T _j = 25 °C | | 1200 | V |
| lc | T _j = 175 °C | T _c = 25 °C | 336 | Α |
| | | T _c = 80 °C | 258 | А |
| I _{Cnom} | | | 225 | Α |
| I _{CRM} | | | 450 | Α |
| V _{GES} | | | -20 20 | V |
| t _{psc} | $V_{CC} = 800 V$ $V_{GE} \le 15 V$ $V_{CES} \le 1200 V$ | T _j = 150 °C | 8 | μs |
| Tj | | | -40 175 | °C |
| Inverse d | iode | | | |
| V _{RRM} | T _j = 25 °C | | 1200 | V |
| l _F | – T _j = 175 °C | T _c = 25 °C | 300 | Α |
| | | T _c = 80 °C | 225 | Α |
| I _{FRM} | | | 450 | А |
| I _{FSM} | t _p = 10 ms, sin 180°, T _i = 25 °C | | 1161 | Α |
| Tj | | | -40 175 | °C |
| Module | | 1 | | |
| I _{t(RMS)} | | | 600 | А |
| T _{stg} | module without TIM | | -40 125 | °C |
| V _{isol} | AC sinus 50Hz, t = 1 min | | 4000 | V |

Characteristics

| Symbol | Conditions | | min. | typ. | max. | Unit |
|----------------------|--|-------------------------|-------|------|-------|------|
| IGBT | | | | | | |
| V _{CE(sat)} | I _C = 225 A | T _j = 25 °C | | 1.56 | 1.88 | V |
| | V _{GE} = 15 V chiplevel | T _j = 150 °C | | 1.80 | | V |
| V _{CE0} | chiplevel | T _j = 25 °C | | 0.84 | 0.91 | V |
| | | T _j = 150 °C | | 0.72 | | V |
| r _{CE} | V _{GE} = 15 V chiplevel | T _j = 25 °C | | 3.2 | 4.3 | mΩ |
| | | T _j = 150 °C | | 4.8 | | mΩ |
| V _{GE(th)} | $V_{CE} = 10 \text{ V}, \text{ I}_{C} = 22.5 \text{ mA}$ | | 5.4 | 6 | 6.6 | V |
| I _{CES} | $V_{GE} = 0 V, V_{CE} = 1200 V, T_j = 25 °C$ | | | | 2.3 | mA |
| Cies | 1011 | f = 1 MHz | | 48.0 | | nF |
| Coes | V _{CE} = 10 V V _{GE} = 0 V | f = 1 MHz | | 1.49 | | nF |
| C _{res} | | f = 1 MHz | | 0.57 | | nF |
| Q _G | V _{GE} = -8V + 15V | | | 2250 | | nC |
| R _{Gint} | T _j = 25 °C | | | 1.3 | | Ω |
| t _{d(on)} | $\begin{array}{l} I_{C} = 225 \text{ A} \\ V_{GE} = +15 / -15 \text{ V} \\ R_{G \text{ on}} = 1.5 \ \Omega \\ R_{G \text{ off}} = 1.5 \ \Omega \\ di/dt_{on} = 5700 \text{ A/}\mu\text{s} \\ di/dt_{off} = 2200 \text{ A/}\mu\text{s} \end{array}$ | T _j = 150 °C | | 210 | | ns |
| t _r | | T _j = 150 °C | | 45 | | ns |
| Eon | | T _j = 150 °C | | 15 | | mJ |
| t _{d(off)} | | T _j = 150 °C | | 350 | | ns |
| t _f | | T _j = 150 °C | | 90 | | ns |
| E _{off} | | T _j = 150 °C | | 24 | | mJ |
| R _{th(j-c)} | per IGBT | | | | 0.141 | K/W |
| R _{th(c-s)} | per IGBT (λ _{grease} =0.81 W/(m*K)) | | | 0.03 | | K/W |
| R _{th(c-s)} | per IGBT, pre-appli material | | 0.021 | | K/W | |



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| Symbol | Conditions | min. | typ. | max. | Unit | |
|-----------------------|--|-------------------------|------|-------------|-------|-----|
| Inverse d | iode | | | | | |
| $V_F = V_{EC}$ | I _F = 225 A | T _j = 25 °C | | 2.17 | 2.49 | V |
| | V _{GE} = 0 V chiplevel | T _j = 150 °C | | 2.12 | 2.42 | V |
| V _{F0} | chiplevel | T _j = 25 °C | | 1.30 | 1.50 | V |
| | | T _j = 150 °C | | 0.90 | 1.10 | V |
| ŕ _F | chiplevel | T _j = 25 °C | | 3.9 | 4.4 | mΩ |
| | | T _j = 150 °C | | 5.4 | 5.9 | mΩ |
| I _{RRM} | $I_{F} = 225 \text{ A}$ di/dt _{off} = 5700 A/µs | T _j = 150 °C | | 270 | | Α |
| Q _{rr} | | T _j = 150 °C | | 37 | | μC |
| E _{rr} | V _{GE} = -15 V V _{CC} = 600 V | T _j = 150 °C | | 18 | | mJ |
| R _{th(j-c)} | per diode | | | | 0.186 | K/W |
| R _{th(c-s)} | per diode (λ _{grease} =0 | .81 W/(m*K)) | | 0.045 | | K/W |
| R _{th(c-s)} | per diode, pre-applied phase change material | | | 0.036 | | K/W |
| Module | | | | | | |
| L _{CE} | | | | 20 | | nH |
| R _{CC'+EE'} | measured per switch | T _C = 25 °C | | 1.2 | | mΩ |
| | | T _C = 125 °C | | 1.65 | | mΩ |
| R _{th(c-s)1} | calculated without thermal coupling | | | 0.009 | | K/W |
| R _{th(c-s)2} | including thermal coupling, T_s underneath module (λ_{grease} =0.81 W/ (m*K)) | | | 0.013 | | K/W |
| R _{th(c-s)2} | including thermal coupling, T_s underneath module, pre-applied phase change material | | | 0.010 | | K/W |
| Ms | to heat sink (M5) | | 3 | | 6 | Nm |
| Mt | | to terminals (M6) | 3 | | 6 | Nm |
| | | | | | | Nm |
| w | | | | | 350 | g |
| Temperat | ure Sensor | | | | | |
| R ₁₀₀ | T _c =100°C (R ₂₅ =5 kΩ) | | | 493 ± 5% | | Ω |
| B _{100/125} | R _(T) =R ₁₀₀ exp[B _{100/125} (1/T-1/T ₁₀₀)]; T[K]; | | | 3550 ±2% | | к |

























Fig. 8: Typ. switching times vs. gate resistor R_G







SEMiX 3p



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This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

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